Automotive Electronics Council Component Technical Committee





About the Authors





Cristina Mota Caetano
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Received Masters in Material Science from IST (Technical University of Lisbon). In 1997, started as R&D engineer, with Siemens Matsushita, Germany. From 1999 to 2012, held various R&D and Material & Process Development management roles at EPCOS and KEMET Electronics. Since 2012, have served as the Technical Product Marketing Director for the Tantalum Product Business Unit at KEMET, an Yageo Company,



Keith Moore
Product Management Director,
Tantalum / Aluminum Polymer
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Graduated with degrees in Chemistry and Chemical Engineering. From 1997 to 2015, served in various technical roles focused on the development and manufacturing of tantalum and aluminum products. In 2015, moved into KEMET's product management team as a technical product manager. During which time, served as the ECIA chair for P2-5 Solid Electrolytic Capacitors (Tantalum, Niobium, Aluminum) committee and as the US delegate for IEC TC40 (Capacitors and Resistors for Electronic Equipment) meetings. In 2020, accepted product management responsibilities for Tantalum and Aluminum polymer products.



Rosa Davila
Technical Product Manager
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Holds a Bachelor of Science in Industrial Chemistry and a Masters in Materials Science. Joined KEMET in 2010 as a New Product Development Engineer and has held various engineering positions for Tantalum PBU. Since June 2021, has worked as Technical Product Manager for Ta and Al Polymer Capacitors. Supports customers in Americas, as well as global SSD and HDD customers. Currently serves as the ECIA chair for P2-5 Solid Electrolytic Capacitors (Tantalum, Niobium, Aluminum) committee and as the US delegate for IEC TC40 (Capacitors and Resistors for Electronic Equipment) meetings.

Outline



- > Trends and Challenges
- > Application and Capacitor Requirements
- Product Offering
- Product Capability
- > Future Direction

Trends and Challenges



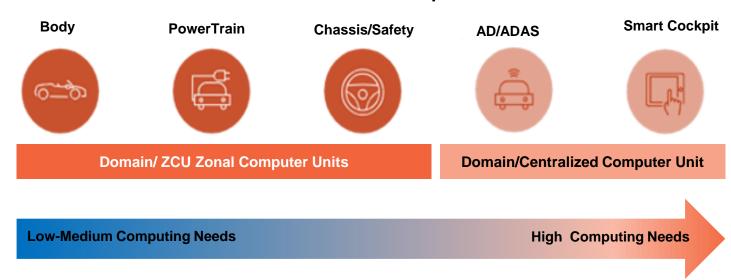
Rise of Components

Rise of Software-Defined Vehicles Rise of Domain, Zonal, and Central Compute Units

Trends and Challenges



Automotive Domain Requirements



	Electronic Compute Unit (ECU)	Domain Compute Unit (DCU)	Zonal Compute Unit (ZCU)	Central Compute Unit (CCU)
CAGR 2023-2030 (%)	-2%	+29%	+44%	+45%
Projected Value 2030 (\$B)	\$73B	\$44B	\$3B	\$10B

Source: McKinsey Center for Future Mobility: https://www.mckinsey.com/industries/semiconductors/our-insights/getting-ready-for-next-generation-ee-architecture-with-zonal-compute#/

Trends and Challenges



SENSING Data Aquisition

GPS LIDAR CAMERA RADAR

PERCEPTION Data Processing

Localization
Object Recognition
Object Tracking

DECISION Makes decisions and issue commands

Prediction
Path Planning
Obstacle Avoidance

Operating System

Hardware Platform

Increase Autonomy Level → Increase on Processing Capabilities



Volumetric Efficiency



Thermal Management and Extended Mission Profiles



Efficient Power Management

Application and Capacitor Requirements



<u>Application</u>	<u>Capacitor</u>
<u>Requirements</u>	<u>Requirements</u>

Smaller Components

Higher Cap Per Unit Volume

Lower ESR,
Lower Thermal Resistance

Higher Reliability

Higher Category Temperature,
Longer Life

Automotive Polymer Capacitor AEC-Q200 Requirements



Stress	Condition			
High Temperature Exposure (Storage)	MIL-STD-202 Method 108 (125°C, Unpowered, 1000 hours)			
Temperature Cycling	JESD22 Method JA-104 (-55°C to 125°C, 1000 Cycles)			
Biased Humidity	MIL-STD-202 Method 103 (85°C, 85%RH, V _r , 1000 hours)			
High Temperature Operational Life	MIL-STD-202 Method 108 (125°C, 0.67 V _r , 1000 hours)			
External Visual and Physical Dimensions	MIL-STD-883, method 2009 and JESD22-B100			
Resistance to Solvents	MIL-STD-202 Method 215			
Mechanical Shock	MIL-STD-202 Method 213			
Vibration	MIL-STD-202 Method 204			
Resistance to Soldering Heat	MIL-STD-202 Method 210			
Solderability	J-STD-002			
Electrical Characterization	User specification			
Terminal Strength	AEC-Q200-006			

Source:

AEC-Q200 Rev E - March 20th, 2023 - Table 1 - Stress Qualification for Tantalum (MnO₂ and Polymer) and Niobium Capacitors

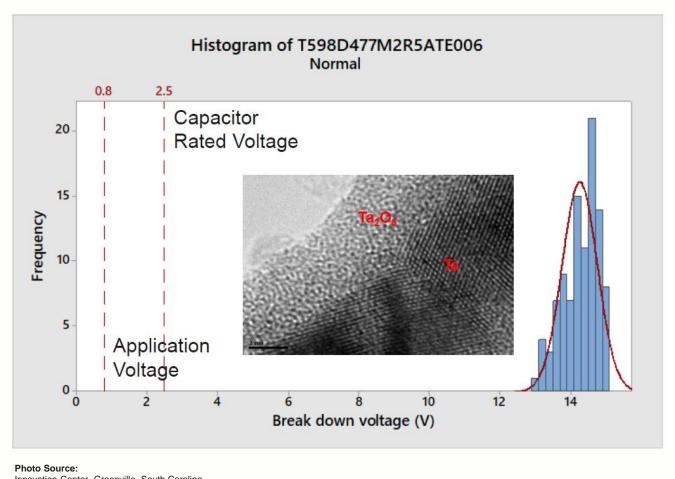
Automotive Polymer Capacitor Product Offering



Size Range (metric)	3.2 mm x 1.6 mm x 1.2 mm 7.3 mm x 4.3 mm x 4.0 mm			
Capacitance Range - μF	1 - 680			
Voltage Range – Volts	2.5 - 75			
Category Temperature - °C	125 - 150			
Lowest ESR (25°C, 100kHz) – mΩ	6			
Maximum Ripple Current (+45°C, 100kHz) - Amps	8.7			







- High Volumetric Efficiency
- Conservative Design
- Robust Dielectric

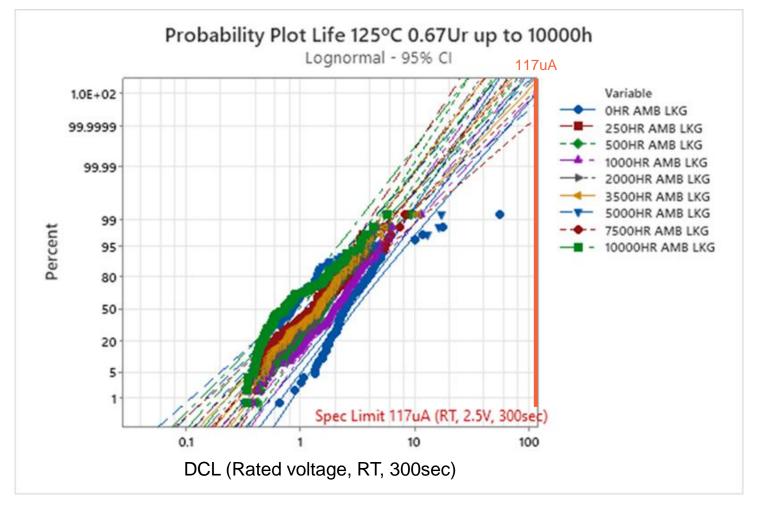
Innovation Center, Greenville, South Carolina

High Resolution TEM Transmission Electron Microscope – Crystalline Structure of Tantalum and Amorphous structure of the dielectric anodic oxide Ta₂O₅



Extended 125°C / 0.67 Vr Life Testing, 2,000 hr → 10,000 hr

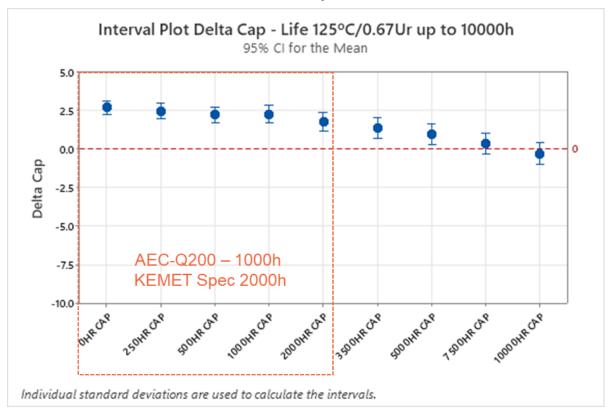




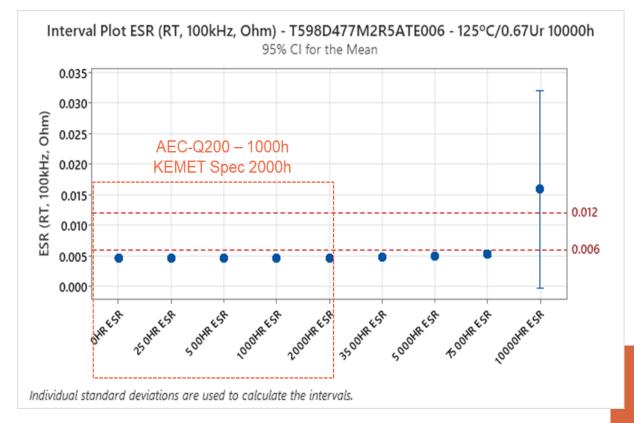


Extended 125°C / 0.67 Vr Life Testing, 2,000 hr > 10,000 hr

120 Hz Capacitance



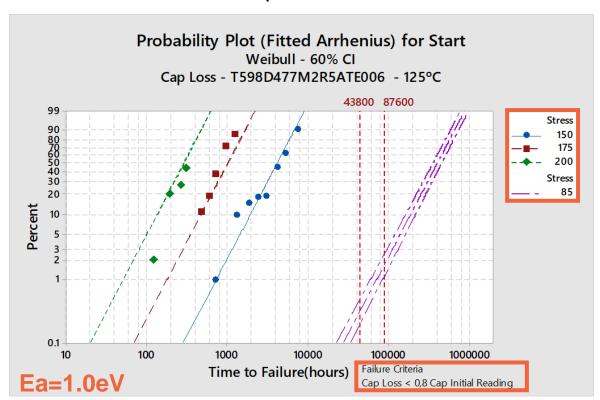
100kHz ESR



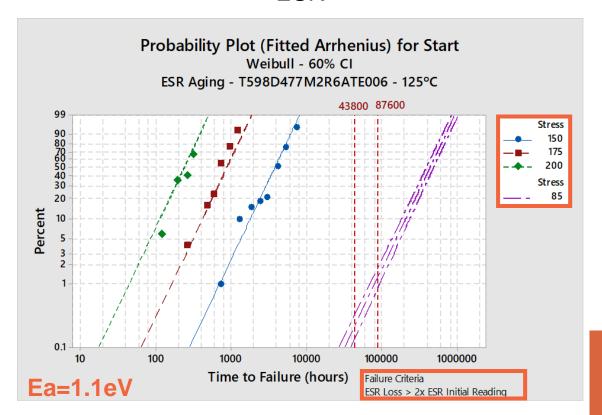
YAGEO§

Capacitance and ESR Loss Modelling

Capacitance

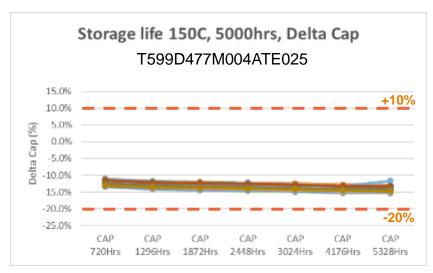


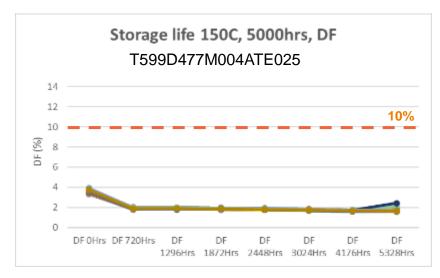
ESR

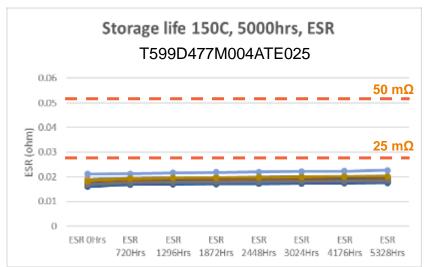


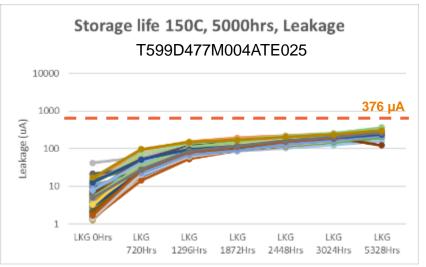
Extended Category Temperature, 125°C → 150°C





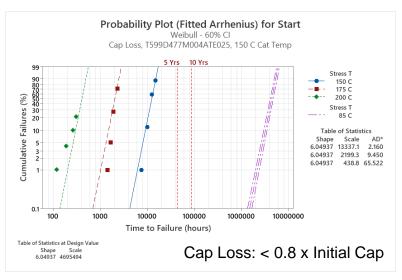


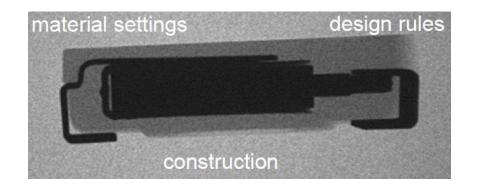


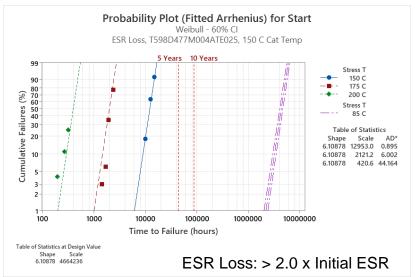


Extended Category Temperature, 125°C → 150°C









Temperature Reference (°C)

Ea - activation energy (eV)

Boltzman Constant

150

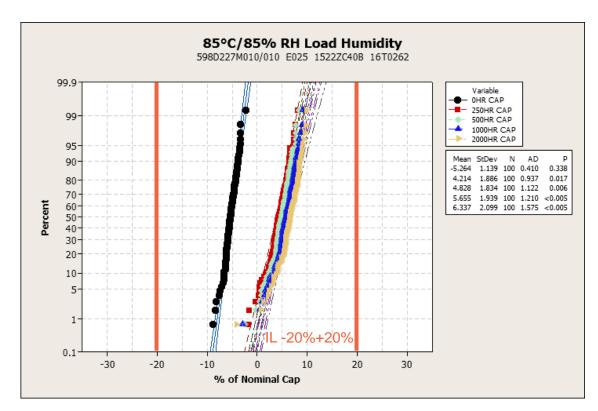
1.18

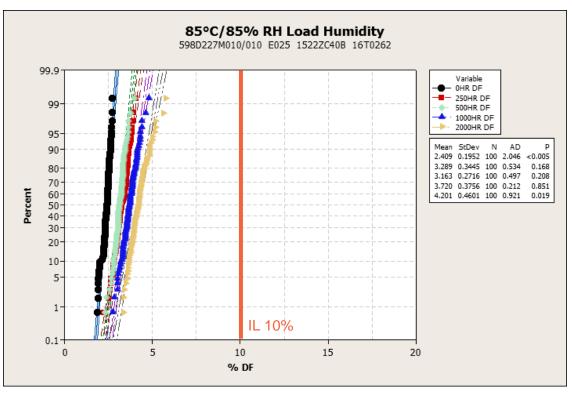
8.62E-05

Temperature (°C)	Accelaration Temp (x	(2)	Lo	Lx (h)	Years
25	785938		5000	3929692465	448595
40	86960		5000	434798985	49635
65	3423		5000	17116400	1954
75	1069		5000	5345397	610
76	955		5000	4775620	545
85	356		5000	1781493	203
90	210		5000	1052072	120
100	77		5000	382794	44
105	47		5000	235579	27
111	27		5000	133780	15
125	8		5000	38177	4



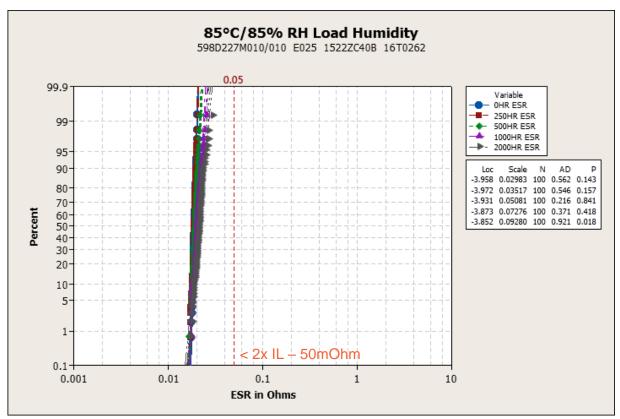
Extended 85°C / 85%RH / Vr Humidity Bias, 1000 h → 2000h

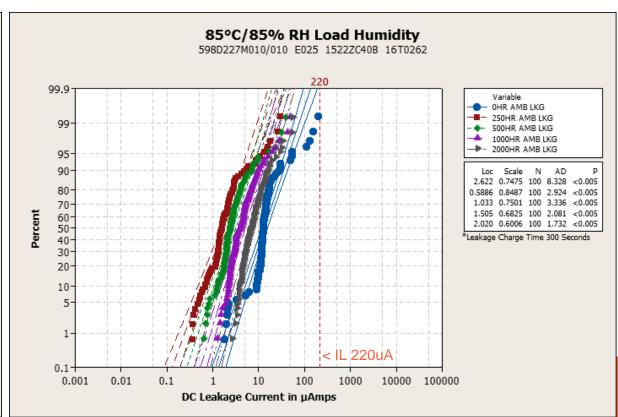






Extended 85°C / 85%RH / Vr Humidity Bias, 1000 h → 2000h





Future Direction



